

**CERAMICS** INTERNATIONAL

www.elsevier.com/locate/ceramint

Ceramics International 35 (2009) 2715-2718

# Dielectric properties and microstructures of CaSiO<sub>3</sub> ceramics with B<sub>2</sub>O<sub>3</sub> addition

Huan-ping Wang, Shi-qing Xu\*, Shui-qin Lu, shi-long Zhao, Bao-ling Wang

College of Materials Science and Engineering, China Jiliang University, Hangzhou 310018, China Received 1 December 2008; received in revised form 16 January 2009; accepted 2 March 2009 Available online 27 March 2009

### **Abstract**

The effects of  $B_2O_3$  additives on the sintering behavior, microstructure and dielectric properties of  $CaSiO_3$  ceramics have been investigated. The  $B_2O_3$  addition resulted in the emergence of  $CaO-B_2O_3-SiO_2$  glass phase, which was advantageous to lower the synthesis temperature of  $CaSiO_3$  crystal phase, and could effectively lower the densification temperature of  $CaSiO_3$  ceramic to as low as 1100 °C. The 6 wt%  $B_2O_3$ -doped  $CaSiO_3$  ceramic sintered at 1100 °C possessed good dielectric properties:  $\varepsilon_r = 6.84$  and  $\tan \delta = 6.9 \times 10^{-4}$  (1 MHz). Crown Copyright © 2009 Published by Elsevier Ltd and Techna Group S.r.l. All rights reserved.

Keywords: C. Dielectric properties; Microstructure; CaSiO<sub>3</sub> ceramic; B<sub>2</sub>O<sub>3</sub> addition

## 1. Introduction

Low temperature co-fired ceramic (LTCC) technology has been playing an important role in modern wireless communication systems. In order to process ceramic with electrode material, such as 30 Pd/70 Ag (mp 1167 °C) and silver (mp 961 °C), it is required to sinter the dielectrics at temperatures lower than the melting temperature of the co-fired electrode material. Research on the development of co-fired dielectrics with different dielectric constants  $\varepsilon_r$  has been going for years to fill the need for various RF ranges [1–6]. However, low  $\varepsilon_r$  material is still the most popularly used one, such as DuPont 951 ( $\varepsilon_r$  7.8,  $Q \times f$  700 GHz at 3 GHz,  $\tau_f$  8 ppm/°C), since it provides fast transmission in communication systems [7,8].

CaSiO<sub>3</sub> ceramic was proved as a low-permittivity dielectric ceramic system and possessing good dielectric properties:  $\varepsilon_r = 5$ ,  $\tan \delta = (1.0-3.0) \times 10^{-4}$  [9]. However, the sintering temperature range of pure CaSiO<sub>3</sub> was very narrow and it was difficult to obtain dense CaSiO<sub>3</sub> ceramics materials by the traditional solid-state preparation process [10]. The synthesis and microwave dielectric properties of CaSiO<sub>3</sub> nanopowder prepared by sol–gel method have been investigated, and it was

In order to improve the sintering characteristic, the study on the synthesis of CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> (CBS) glass-ceramics and decreasing sintering temperature with aids have been investigated. Zhu et al. found that the optimal sintering temperature for CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass-ceramic is 820 °C for 15 min, and the glass-ceramic possesses excellent dielectric properties:  $\varepsilon_{\rm r}=6.5$ ,  $\tan\delta<2\times10^{-3}$  at 10 MHz with the major phases are CaSiO<sub>3</sub>, CaB<sub>2</sub>O<sub>4</sub> and SiO<sub>2</sub> [12]. Chang and co-workers demonstrated that the dielectric properties of the CBS system which comprised of CaSiO<sub>3</sub>, Ca<sub>6</sub>Si<sub>4</sub>O<sub>3</sub> and CaB<sub>2</sub>O<sub>4</sub> are:  $\varepsilon_{\rm r}=5.1$ ,  $\tan\delta=0.0013$  (1 GHz) [13,14]. Cai et al. reported that the excessive SiO<sub>2</sub> and clay can reduce the sintering temperature (1170–1230 °C) of CaSiO<sub>3</sub>, and the dielectric properties are:  $\varepsilon_{\rm r}=7.0$ –9.0,  $\tan\delta=(1.0$ –5.0)  $\times$  10<sup>-4</sup> [9].

In this work, B<sub>2</sub>O<sub>3</sub> was used as the sintering aid to lower the sintering temperature of CaSiO<sub>3</sub> ceramic. The resultant dielectric properties were analyzed based upon the densification, the X-ray diffraction patterns and the microstructures of the ceramics.

# 2. Experimental procedure

Specimen powders were prepared by a conventional solidstate method. High-purity oxide powders (>99.5%): CaCO<sub>3</sub>,

also difficult to obtain dense CaSiO<sub>3</sub> ceramics by sintering the CaSiO<sub>3</sub> nanopowders at 1280–1320 °C [11].

<sup>\*</sup> Corresponding author. Tel.: +86 571 86835781; fax: +86 571 28889527. E-mail address: sxucjlu@hotmail.com (S.-q. Xu).

 $SiO_2$  and  $B_2O_3$  were used as raw materials. The powders were weighed according to the composition of  $CaSiO_3$ , and ground in ethanol for 24 h in a balling mill with agate balls. Prepared powders were dried and calcined at  $1100-1200\,^{\circ}C$  for 2 h in air. The powders calcined at  $1200\,^{\circ}C$  were mixed as desired composition of  $CaSiO_3$  with 0.5-8 wt%  $B_2O_3$  additions and remilled for 24 h. The fine powder together with the organic binder (5 wt% PVA) was pressed into pellets with dimensions of 15 mm in diameter and 5 mm in thickness. These pellets were sintered at temperatures of  $1000-1200\,^{\circ}C$  for 2 h in air with the heating rate of  $5\,^{\circ}C/min$ .

The crystalline phases of calcined powders and sintered ceramics were identified by X-ray diffraction pattern (XRD, ARL XTRA, Cu  $K_{\alpha}$ ). The microstructure observation of the sintered ceramics was performed by means of scanning electron microscopy (SEM, JSM-5601). The bulk densities of the sintered pellets were measured by the Archimedes method. The dielectric constant ( $\varepsilon_r$ ) and dielectric loss ( $\tan \delta$ ) at room temperature were determined from capacitance measurements by an LCR meter (HEWLETT PACKARD 4278A) at 1 MHz, and the electric voltage value was 1 V. The dielectric constant was calculated from a parallel-plate capacitor equation, e.g.,  $\varepsilon_r = Cd/\varepsilon_0 A$ , where C was the capacitance of the specimens, d and A were, respectively, the thickness and the area of the electrode, and  $\varepsilon_0$  was the dielectric permittivity of vacuum (8.854  $\times$  10<sup>-12</sup> F/m). Silver paste was used for the electrodes.

# 3. Results and discussion

Fig. 1 shows the X-ray diffraction patterns of  $CaCO_3$ – $SiO_2$  powders calcined at different temperatures. For the sample calcined at  $1100~^{\circ}C$ , the  $SiO_2$  phase was predominant with a great deal of  $CaSiO_3$  phase. As the calcination temperature was raised to  $1200~^{\circ}C$ , the  $CaSiO_3$  phase became the main phase accompanied with a little  $SiO_2$  phase.

The X-ray diffraction patterns of  $CaSiO_3$  ceramics sintered at 1100 °C with different  $B_2O_3$  additions are shown in Fig. 2. With 0.5 wt%  $B_2O_3$  addition, the single crystal phase of  $CaSiO_3$ 

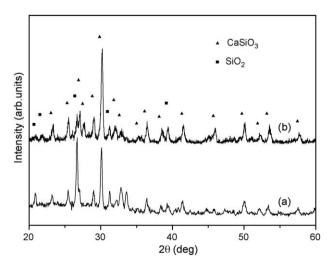


Fig. 1. X-ray diffraction patterns of CaCO\_3–SiO\_2 powders calcined at (a) 1100  $^{\circ}C$  and (b) 1200  $^{\circ}C$  .

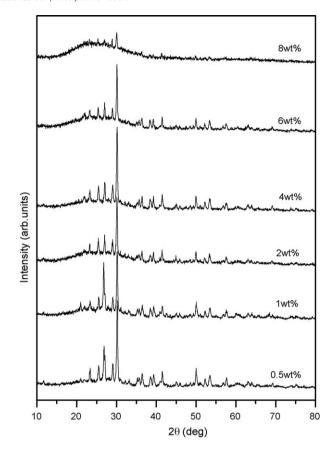


Fig. 2. X-ray diffraction patterns of CaSiO\_3 ceramics sintered at 1100  $^{\circ}C$  with different  $B_2O_3$  additions.

was obtained, and no second phase was observed, which indicated that the addition of  $B_2O_3$  could lower the synthesis temperature of  $CaSiO_3$  crystal phase. Moreover, it is clear that the diffraction peaks of  $CaSiO_3$  were weakened and the amorphous phase was increased with the  $B_2O_3$  content. The results showed that the  $B_2O_3$  addition resulted in the emergence of  $CaO-B_2O_3-SiO_2$  glass phase, which was advantageous to lower the synthesis temperature of  $CaSiO_3$  crystal phase.

The density of B<sub>2</sub>O<sub>3</sub>-doped CaSiO<sub>3</sub> ceramics at different sintering temperatures is shown in Fig. 3. With increasing sintering temperature, the apparent density was found to increase to a maximum value, and higher B<sub>2</sub>O<sub>3</sub> content shifts the obtainable maximum density to a lower temperature. The bulk densities of CaSiO<sub>3</sub> ceramics sintered at 1100 °C with  $2.78 \text{ g cm}^{-3}$ ,  $2.85 \text{ g cm}^{-3}$  and  $2.82 \text{ g cm}^{-3}$ , respectively. The optimal sintering temperatures of CaSiO<sub>3</sub> ceramics with 0.5 wt%, 1-2 wt%, 4 wt%, 6 wt% and 8 wt%  $B_2O_3$  additions were 1200-1250 °C, 1150-1200 °C, 1150 °C, 1100 °C and 1100-1150 °C, separately. The decrease of sintering temperature with the increase of B<sub>2</sub>O<sub>3</sub> addition was due to the augment of CaO-B2O3-SiO2 glass phase, which would transform into liquid phase and promote the sintering process. As it is obvious, the CaSiO<sub>3</sub> ceramic sintered at 1100 °C with 6 wt% B<sub>2</sub>O<sub>3</sub> addition reached above 98% of the theoretical density (the

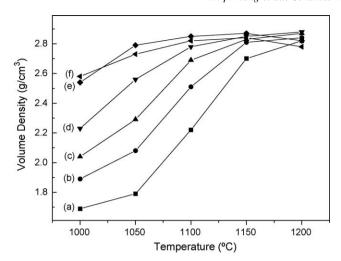


Fig. 3. Dependence of volume density on sintering temperature for  $CaSiO_3$  ceramics with (a) 0.5 wt%, (b) 1 wt%, (c) 2 wt%, (d) 4 wt%, (e) 6 wt% and (f) 8 wt%  $B_2O_3$  additions.

theoretical density of CaSiO<sub>3</sub> ceramic is 2.91 g cm<sup>-3</sup>), which could be co-fired with 30 Pd/70 Ag electrode material.

The microstructures of CaSiO<sub>3</sub> ceramics sintered at 1100 °C with different B<sub>2</sub>O<sub>3</sub> additions are presented in Fig. 4. From picture

(a), it can be seen that the specimen was not dense and the grain did not grow with 0.5 wt% B<sub>2</sub>O<sub>3</sub> addition. Picture (b), picture (c) and picture (d) show that the grain size increased with the increase of B<sub>2</sub>O<sub>3</sub> addition due to the liquid phase effect resulted from the addition of B<sub>2</sub>O<sub>3</sub>, and there were many grains which grow up to 5 μm with 4 wt% B<sub>2</sub>O<sub>3</sub> added in. However, the CaSiO<sub>3</sub> ceramics had many pores with 1-4 wt% B<sub>2</sub>O<sub>3</sub> addition, which indicated that it is difficult to lower down the sintering temperature of CaSiO<sub>3</sub> ceramics to 1100 °C by adding 1–4 wt% B<sub>2</sub>O<sub>3</sub>. This was probably due to an insufficient amount of liquid phase (CaO-B<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> glass phase). When the B<sub>2</sub>O<sub>3</sub> content increased to 6 wt%, the grains of CaSiO<sub>3</sub> ceramic were in close contact and there was little porosity, which was consistent with the result of bulk densities. However, a low grain growth rate was observed by adding 8 wt% B<sub>2</sub>O<sub>3</sub>, which was due to the decreasing of CaSiO<sub>3</sub> phase and the augment of CaO-B<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> glass phase.

The dielectric properties (dielectric constant  $\varepsilon_r$  and dielectric loss  $\tan \delta$ ) of B<sub>2</sub>O<sub>3</sub>-doped CaSiO<sub>3</sub> ceramics sintered at different temperatures (1050–1200 °C) are illustrated in Figs. 5 and 6. The relationships between dielectric properties and sintering temperature followed similar trend to those between density and sintering temperature, due to a fact that a higher density signifying a lower porosity. The dielectric constant ( $\varepsilon_r$ ) increased

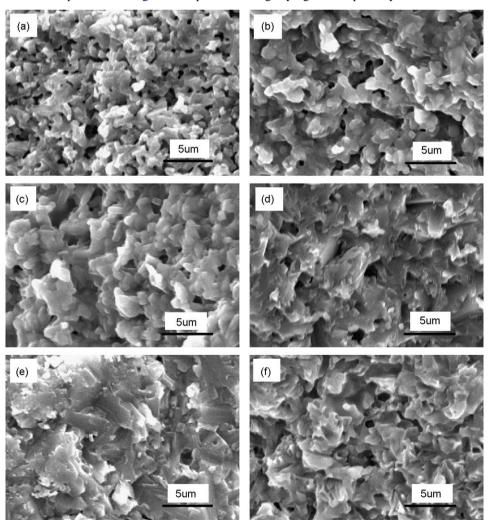


Fig. 4. SEM photographs of CaSiO $_3$  ceramics sintered at 1100  $^{\circ}$ C with (a) 0.5 wt%, (b) 1 wt%, (c) 2 wt%, (d) 4 wt%, (e) 6 wt% and (f) 8 wt%  $B_2O_3$  additions.

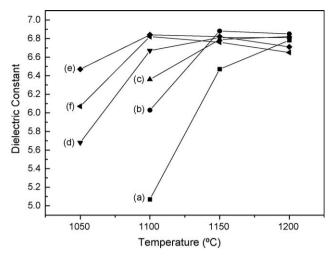


Fig. 5. Dependence of dielectric constant on sintering temperature for  $CaSiO_3$  ceramics with (a) 0.5 wt%, (b) 1 wt%, (c) 2 wt%, (d) 4 wt%, (e) 6 wt% and (f) 8 wt%  $B_2O_3$  additions.

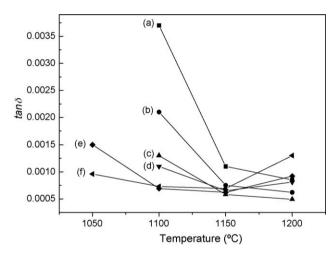


Fig. 6. Dependence of dielectric loss on sintering temperature for  $CaSiO_3$  ceramics with (a) 0.5 wt%, (b) 1 wt%, (c) 2 wt%, (d) 4 wt%, (e) 6 wt% and (f) 8 wt%  $B_2O_3$  additions.

and the dielectric loss (tan  $\delta$ ) decreased with the increasing sintering temperature. Sintered at 1100 °C, the CaSiO<sub>3</sub> ceramic with 6 wt% B<sub>2</sub>O<sub>3</sub> addition possessed good dielectric properties:  $\varepsilon_{\rm r}=6.84$  and tan  $\delta=6.9\times10^{-4}$  (1 MHz), which was a better result than the dielectric properties of CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass-ceramic [12–14]. The dielectric properties of CaSiO<sub>3</sub> ceramic with 8 wt% B<sub>2</sub>O<sub>3</sub> addition were:  $\varepsilon_{\rm r}=6.76$  and tan  $\delta=7.3\times10^{-4}$  (1 MHz). It suggested that the dielectric constant decreased and the dielectric loss increased with the increasing of B<sub>2</sub>O<sub>3</sub> addition, although it was advantageous to lower the sintering temperature by adding sufficient B<sub>2</sub>O<sub>3</sub>. These results also indicated that the dielectric constant of CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass was lower than which of CaSiO<sub>3</sub> ceramic and the dielectric loss of CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass was higher than which of CaSiO<sub>3</sub> ceramic.

## 4. Conclusion

The dielectric properties and microstructures of B<sub>2</sub>O<sub>3</sub>-doped CaSiO<sub>3</sub> ceramics were investigated. B<sub>2</sub>O<sub>3</sub> was not detected in

the ceramics but residual as a CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass phase. The emergence of CaO–B<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> glass phase, acting as a sintering aid, can effectively lower the synthesis temperature of CaSiO<sub>3</sub> crystal phase and the sintering temperature of CaSiO<sub>3</sub> ceramic. Sintered at 1100 °C, the 6 wt% B<sub>2</sub>O<sub>3</sub>-doped CaSiO<sub>3</sub> ceramic possesses good dielectric properties:  $\varepsilon_r = 6.84$  and tan  $\delta = 6.9 \times 10^{-4}$  (1 MHz), which can be co-fired with 30 Pd/70 Ag electrode material.

# Acknowledgement

This work is supported by Program for New Century Excellent Talents in University (grant NO NCET-07-0786), the Nature Science Foundation of Zhejiang Province (grant NO R406007) and the Science Technology of Zhejiang Province (grant NO 2008C21054).

#### References

- [1] C.L. Huang, S.S. Liu, Microwave dielectric properties of a new ceramic system (1-x)(Mg<sub>0.95</sub>Zn<sub>0.05</sub>)TiO<sub>3</sub>-xCaTiO<sub>3</sub> at microwave frequencies, Mater. Lett. 62 (21-22) (2008) 3773-3775.
- [2] J.B. Lim, K.H. Cho, S. Nahm, J.H. Paik, J.H. Kim, Effect of BaCu(B<sub>2</sub>O<sub>5</sub>) on the sintering temperature and microwave dielectric properties of BaO-Ln<sub>2</sub>O<sub>3</sub>-TiO<sub>2</sub> (Ln=Sm, Nd) ceramics, Mater. Res. Bull. 41 (10) (2006) 1868–1874.
- [3] D. Zou, Q.L. Zhang, H. Yang, S.C. Li, Low temperature sintering and microwave dielectric properties of Ba<sub>2</sub>Ti<sub>3</sub>Nb<sub>4</sub>O<sub>18</sub> ceramics for LTCC applications, J. Eur. Ceram. Soc. 28 (14) (2008) 2777–2782.
- [4] P.V. Bijumon, M.T. Sebastian, Influence of glass additives on the microwave dielectric properties of Ca<sub>5</sub>Nb<sub>2</sub>TiO<sub>12</sub> ceramics, Mat. Sci. Eng. B 123 (2005) 31–40.
- [5] N. Santha, M.T. Sebastian, Low temperature sintering and microwave dielectric properties of Ba<sub>4</sub>Sm<sub>9.33</sub>Ti<sub>18</sub>O<sub>54</sub> ceramics, Mater. Res. Bull. 43 (8–9) (2008) 2278–2284.
- [6] K.W. Kang, H.T. Kim, M. Lanagan, T. Shrout, Low-temperature sintering and microwave dielectric properties of CaTi<sub>1-x</sub>(Fe<sub>0.5</sub>Nb<sub>0.5</sub>)<sub>x</sub>O<sub>3</sub> ceramics with B<sub>2</sub>O<sub>3</sub> addition, Mater. Res. Bull. 41 (7) (2006) 1385–1391.
- [7] C.L. Huang, C.L. Pan, LeeF W.C., Microwave dielectric properties of mixtures of glass-forming oxides Zn-B-Si and dielectric ceramics MgTiO<sub>3</sub>-CaTiO<sub>3</sub> for LTCC applications, J. Alloy Compd. 462 (1–2) (2008) L5–L8.
- [8] Q.L. Zhang, H. Yang, J.L. Zou, Low-temperature sintering of (Zn<sub>0.8</sub> Mg<sub>0.2</sub>)<sub>2</sub>SiO<sub>4</sub>-TiO<sub>2</sub> ceramics, Mater. Lett. 62 (23) (2008) 3872–3874.
- [9] W. Cai, T. Jiang, X.Q. Tan, Q. Wei, Y. Li, Development of low dielectric constant calcium silicate fired at low temperature, Elec. Compd. Mater. 21 (2002) 16–18.
- [10] R.P.S. Chakradhar, B.M. Nagabhushana, G.T. Chandrappa, K.P. Ramesh, J.L. Rao, Solution combustion derived nanocrystalline macroporous wollastonite ceramics, Mater. Chem. Phys. 95 (2006) 169– 175.
- [11] H.P. Wang, Q.L. Zhang, H. Yang, H.P. Sun, Synthesis and microwave dielectric properties of CaSiO<sub>3</sub> nanopowder by the sol-gel process, Ceram. Int. 34 (6) (2008) 1405–1408.
- [12] H.K. Zhu, M. Liu, H.Q. Zhou, L.Q. Li, A.G. Lv, Study on properties of CaO-SiO<sub>2</sub>-B<sub>2</sub>O<sub>3</sub> system glass-ceramic, Mater. Res. Bull. 42 (6) (2007) 1137–1144
- [13] C.R. Chang, J.H. Jean, Crystallization kinetics and mechanism of low-dielectric, low-temperature, cofirable CaO-B<sub>2</sub>O<sub>3</sub>-SiO<sub>2</sub> glass-ceramics, J. Am. Ceram. Soc. 82 (1999) 1725–1732.
- [14] S.H. Wang, H.P. Zhou, L. Qiao, A ceramic for the high frequency multilayer chip inductor, Mater. Mech. Eng. 27 (2003) 17–20.